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Complete if Known

Application Number	
Filing Date	
First Named Inventor	Gattiker
Art Unit	
Examiner Name	
Attorney Docket Number	AUS920030653US1

Sheet	1	of	3
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U. S. PATENT DOCUMENTS

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FOREIGN PATENT DOCUMENTS

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Examiner Signature	<i>C. J. [Signature]</i>	Date Considered	4/27/05
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STATEMENT BY APPLICANT**

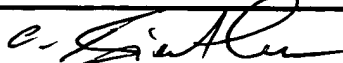
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	Filing Date	
	First Named Inventor	Gattiker
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Sheet 2 of 3	Attorney Docket Number	AUS920030653US1

NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
CHB		KRUSEMAN, ET AL. The Future of IDDQ Testing, IEEE International Test Conference Proceedings, 2001	
CHB		THIBEAULT, Improving Delta-IDDQ-based Test Methods, IEEE International Test Conference Proceedings, 2000	
CHB		MAXWELL, ET AL. Current Ratios: A Self-Scaling Technique, IEEE International Test Conference Proceedings, 1999	
CHB		GATTIKER, ET AL. Current Signatures, IEEE VLSI Test Symposium Proceedings, 1996	
CHB		OKUDA, Eigen-Signatures for Regularity-based IDDQ Testing, IEEE VLSI Test Symposium Proceedings, 2002	
CHB		OKUDA, DECOUPLE: Defect Current Detection in Deep Sub-micron IDDQ, IEEE International Test Conference Proceedings, 2000	
CHB		VARIYAM, Increasing the IDDQ Test Resolution Using Current Prediction, IEEE International Test Conference Proceedings, 2000	
CHB		BERGMAN, ET AL., Improved IDDQ Testing With Empirical Linear Prediction, IEEE International Test Conference Proceedings, 2002	
CHB		HENRY, ET AL., Burn-in Elimination of a High Volume Microprocessor Using IDDQ, IEEE International Test Conference Proceedings, 1996	
CHB		NIGH, Application and Analysis of IDDQ Diagnostic Software, IEEE International Test Conference Proceedings, 1997	

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Sheet 3	of 3	Attorney Docket Number	AUS920030653US1

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CHK		LAVO, ET AL., Eliminating the Ouija Board: Automatic Thresholds and Probabilistic IDDQ Diagnosis, IEEE International Test Conference Proceedings, 1999	
CHK		GATTIKER, Current Signatures for Integrated Circuit Test Strategy Advisor, Carnegie Mellon University, Ph.D. Dissertation	

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